ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention

SEGMENTED ALGORITHMIC PATTERN GENERATOR

Application Number:

Confirmation Number:

First Named Applicant:

Amy Gottsche

Attorney Docket Number:

BUR920030165US1

Art Unit:

Examiner:

Search string:

(5872797 or 6044480 or 6314540 or 5862149 or 6615380 or 5802075 or 5097468

or 5430736 or 5010552 or 4994732 or 6212667 or 6092225).pn

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

八	į,	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
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V		2	6044480	2000-03-28	Keen			
	П	3	6314540	2001-11-06	Huott et al.			
	П	4	5862149	1999-01-19	Carpenter et al.			
	П	5	6615380	2003-09-02	Kapur et al.			
	П	6	5802075	1998-09-01	Carpenter et al.			
	П	7	5097468	1992-03-17	Earlie			·
	П	8	5430736	1995-07-04	Takeoka et al.			
		9	5010552	1991-04-23	Dias et al.			
П		10	4994732	1991-02-19	Jeffrey et al.	•		
T		11	6212667	2001-04-03	Geer et al.			
		12	6092225	2000-07-18	Gruodis et al.			

Signature

n Spxaminer Name	, Date
Ash J. July	9/8/64

Supplemental Form PTO-1449 (Modified)				y Docket No.: 0030165US1		Serial No: 10/710802				
	ND PUBLICATIONS FOR AICLOSURE STATEMENT	PLICANT'S	Applicant: Amy J. Gottsche, et al.							
(Use several sheets if n	ecessary) Pa	ge I of I	Filing C			Group: Unassigned				
REFERENCE DESI	GNATION	U.S. P	ATENT	DOCUMENTS			-			
EXAMINERS INITIALS	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING (IF API	_		
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EXAMINER	John J. Ja	la	2	DATE CONSIDER	ED	9/8/06				
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